INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(Use several sheets if necessary)

Attorney Docket No.: 8020-1021-1	Application No.: NEW
Applicant: Yoshihisa MATSUBARA	
Filing Date:	Group Art Unit:

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing date (if appropriate)
ap	5,903,053	May 1999	lijima et al.			
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ap	"International Reliability Physics Symposium", 1997 Tutorial Notes, pages 3.30-3.33, IEEE
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DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

^{*} Abstract provided for the Examiner's convenience